Multiplying Throughput in Backgrinding and Wafer Processing with

Novel Temporary Bonding Solutions

Al Technology, Inc Wafer Processing Adhesives Webinar



Introduction

Today's Presenters

- Robert Gelosa · Sales Engineer
- Amar Chauhan · Sales Manager

To learn more please go to: aitechnology.com/products/wafer-processing-adhesives-and-solutions/

Visit us on the web: **www.aitechnology.com** Send us an email**: ait@aitechnology.com** Give us a call: **1-(609)-799-9388**



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Introduction

Two Distinct Processes

• Different Temporary Bonding Requirements

Wafer Backgrinding + Wafer Processing





Wafer Backgrinding and Thinning



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Presentation Roadmap

Wafer Backgrinding + Wafer Processing

Introduction to AIT Temporary Bonding Solutions

Background + Technology
Processing conditions
Temporary Adhesive: Bonding and Debonding

How AIT can multiply throughputNovel SolutionWPA-LD-350 Product Linefill

WPA-PRCL-350 & WPA-UVR-270

GD-PRCL-350 Product Line

Wafer Backgrinding and Thinning Special Solutions for Special Material

Background

Requirements

Novel Solutions From AI Technology,Inc

BGF7160 and BGF7090

WPA-PRCL-200

GD-BGF 7160 & GD-BGF 7090

GD-WPA-PRCL-300



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Wafer Processing and Backgrinding









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Wafer Backgrinding + Wafer Processing

Introduction to AIT Temporary Bonding Solutions

Motivations	Background + Technology			
for	Processing conditions			
Innovation	Temporary Adhesive: Bonding and Debonding			
How AIT can mu	Itiply throughput			
WPA-LD	-350 Product Line			

WPA-PRCL-350 & WPA-UVR-27

GD-PRCL-350 Product Line

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Wafer Processing

What's motivating changes in wafer processing?



The data visualization is available at OurWorldinData.org. There you find more visualizations and research on this topic.

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Wafer Processing 2.5 & 3D Packaging: IC Integration





https://www.eenewsanalog.com/news/backside-wafer-promises-3d-chip-improvements

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Wafer Processing FOWLP: Size, Performance, Cost



Sharma, Gaurav, et al. "Advanced FOWLP for small form factor and high-performance microcontroller apps." *Chip Scale Review* Mar. Apr 2020: 17-21. Print.

Image: Equipment and Materials for Fan-Out Packaging 2019 report by Yole slideshare.net/Yole_Developpement/equipment-and-materials-for-fanout-packaging-2019-report-by-yole-dveloppement



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WPA-LD	-350 Product Line			
WPA-PRCL-350	& WPA-UVR-270	AI Technology,		
GD-PRCL	-350 Product Line			

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GD-WPA-PRCL-300



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Wafer Processing Processing Example: 3D Packaging and TSV Creation Via First Wafer Fill **BEOL** Etch **FEOL** Thinning TT TI **TSV** 00 Processing Via **Methods** Middle Wafer **BEOL** Fill Etch **FEOL** Thinning TT TI IΙ 00 00 Via Last Wafer Etch Fill **FEOL BEOL** Thinning AI Technology, Inc – Wafer Processing Webinar 12





Wafer Processing

Tough Requirements For Temporary Bonding

Compatible with standard wafer processing

PVD, CVD, Lithography, Etching, ECD, CMP, Etc.

Stable under severe conditions

Low Stress Bonding and De-Bonding Prevent damage to thinned wafer

De-Bonding and cleaning residuals

Determine productivity and yield

Conformable to bumped wafers

Absorb-encapsulate bumps up to 400μm

Application	Type of Topography	Adhesive Thickness	Today's thin Si TTV Requirements
3D	Pad / RDL (<10 μm)	20µm	≤2µm
3D / 2.5D	Micro bump (10 – 40µm)	20 – 70µm	≤4µm
2.5D	C4 bump (70 - 80µm)	$\geq 100 \mu m$	≤5µm

Room Temperature Temporary Bonding/ Debonding Processes for 2.5/ 3D integration. Tim McCrone Applications.Engineer SUSS MicroTec Inc. 430 Indio Way Sunnyvale, CA



No outgassing

Presentation Roadmap

Wafer Backgrinding + Wafer Processing

Introduction to AIT Temporary Bonding Solutions

Innovation	Temporary Adhesive: Bonding and Debonding
for	Processing conditions
Motivations	Background + Technology

How AIT can multiply throughputNovel SolutWPA-LD-350 Product LineImage: Colored co

Wafer Backgrinding and Thinning Special Solutions for Special Material

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Wafer Processing Bonding and De-Bonding: From Backgrinding to Wafer Processing



Wafer Processing Traditional Bonding





Wafer Processing Traditional De-Bonding







Presentation	Roadmap	
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Wafer Backgrinding + Wafer Processing

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How AIT can multiply throughputNovel SolutionsWPA-LD-350 Product LinefromWPA-PRCL-350 & WPA-UVR-270AI Technology,GD-PRCL-350 Product Lineinc

Wafer Backgrinding and Thinning Special Solutions for Special Material

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Wafer Processing AIT Laser De-Bonding Materials

AIT Multilayer Peel and Laser Debonding

- Film format
- Conformable for topographic encapsulation
- 1 layer laser debonding material
 - Sandwiched by thin peel-release layers
- High Tg
- High Modulus

Traditional Laser De-Bonding from AIT

- Film or liquid dispensing
- High Tg
- High modulus
- Focused laser de-bonding
- Conformable for topographic encapsulation



Wafer Processing AIT Laser De-Bonding Materials





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Wafer Processing WPA-LD-350 and WPA-LD-350-L: Laser De-Bonding

Properties

Temporary Bonding Adhesive	WPA-LD-350	WPA-LD-350-L	
Conformable Adhesive Thickness	20 100 200 400	Liquid Form (As	
(μm, for Bumps Absorption)	20, 100, 200, 400	Dispensed)	
Adhesive Stretchability	<u>\20%</u>	> 200/	
(Strain Before Breaking)	/30%	>50%	
Adhesive Tg (°C)	240	240	
Release Liners (Top/Bottom)	50µm/50µm	50µm/50µm	
Supported Carrier	Glass	Glass	
Malt Panding Tomporature / Drossura	140-160°C /	140-160°C/	
Men-bonding remperature/Pressure	10-15 psi	10-15 psi	
Shear Bond Strength at 25°C to 125°C	2,000psi-1,000 psi	2,000psi-1,000 psi	

Adhesive Stability

Temporary Bonding Adhesive	WPA-LD-350	WPA-LD-350-L	
Stability at 250°C	No limitation	No limitation	
(Oxygen-free Condition)			
Stability at 275°C	No limitation	No limitation	
(Oxygen-free Condition)		NO IIIIItation	
Stability at 350°C	>60 min	>60 min.	
(Oxygen-free Condition)	200 11111.		
Vacuum Outgassing Stability	Non-outgassing	Non-outgassing	
	Not affected by	Not affected by	
Solvent and Chemical Stability	acid/base and polar	acid/base and polar	
	solvents	solvents	
Water-Jet and Plating Bath	Not affected by plating	Not affected by plating	
Bond Stability	solution and water	solution and water	

Debonding and Cleaning

Temporary Bonding Adhesive	WPA-LD-350	WPA-LD-350-L
De-bonding Carrier and Device Wafer	Focused Laser	Focused Laser
Cleaning Solvent-Process for Wafer	Specified Solvent	Specified Solvent
Cleaning Solvent-Process for Carrier	Specified Solvent	Specified Solvent





Wafer Processing WPA-LD-PR-350: Multilayer Peel and Laser De-Bonding

Properties		Adhesive Stability		Debonding and Cleaning	
Temporary Bonding Adhesive	WPA-LD-PR-350	Temporary Bonding Adhesive	WPA-LD-PR-350	Temporary Bonding Adhesive	WPA-LD-PR-350
Conformable Adhesive Thickness	100 200 400	Stability at 250°C	No lineitetion	De-bonding Process:	Focused Laser and Peel
(μm, for Bumps Absorption)	100, 200, 400	(Oxygen-free Condition)	No limitation	from Device Wafer	Rlease
Adhesive Stretchability	>30%	Stability at 275°C		Cleaning Solvent-Process for	
(Strain Before Breaking)		(Oxygen-free Condition)	No limitation	Wafer	No Cleaning Required
Adhesive Tg (°C)	240 -55 (Peel-Release Layers)	Stability at 350°C	>10 min.	Cleaning Solvent-Process for	No Cleaning Required
Release Liners (Top/Bottom)	50µm/50µm	(Oxygen-free Condition)	_	Carrier	
Supported Carrier	Glass	Vacuum Outgassing Stability	Non-outgassing		
Melt-Bonding Temperature/Pressure	140-160°C/10-15 psi		Not affected by		
Shear Bond Strength at 25°C to 125°C	2 000nsi-1 000 nsi	Solvent and Chemical Stability	acid/base and polar		
	2,000031-1,000 p31		solvents		
		Water-Jet and Plating Bath	Not affected by plating		
		Bond Stability	solution and water		



Presentation	Roadmap	
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Wafer Backgrinding + Wafer Processing

Introduction to AIT Temporary Bonding Solutions

Background + Technology
Processing conditions
Temporary Adhesive: Bonding and Debonding

How AIT can multiply throughputNovel SolutionsWPA-LD-350 Product LinefromWPA-PRCL-350 & WPA-UVR-270Al Technology,GD-PRCL-350 Product Lineinc



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Wafer Backgrinding and Thinning Special Solutions for Special Material

Background

Requirements

Novel Solutions From AI Technology,Inc

BGF7160 and BGF7090

WPA-PRCL-200

GD-BGF 7160 & GD-BGF 7090

GD-WPA-PRCL-300

Wafer Processing Standard Procedures

Bonding, De-Bonding, and Typical Process Steps

- Spin coat or dispense on carrier
- Dry solvent
- Laminate to active side of wafer
- Backgrind with "water" cleaning
- Stress relief
- Via creation
- Lithography, plating, deposition, etc
- De-bond separate carrier and device wafer
 - Focused laser, heat slide, solvent assist
- Clean device wafer
- Clean carrier





Wafer Processing

Higher Throughput with glass or wafer carrier

AIT Temporary Bonding Adhesive Films

Peel-Release Clean: WPA-PRCL-350 | UV-Release Clean: WPA-UVR-270

Bonding, De-Bonding, and Process Steps

With Novel Solutions by AIT

- Spin coat or dispense on carrier
 Dry solvent
- Laminate to active side of wafer
- Backgrind with "water" cleaning
- Stress relief
- Via creation
- Lithography, plating, deposition, etc
- De-bond separate carrier and device wafer
 - UV or Peel Release
 - Focused laser, heat slide, solvent assist
- - Clean carrier

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NO spin coating. NO drying. NO expensive, intensive, time consuming debonding NO cleaning



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Wafer Processing WPA-PRCL-350 and WPA-UVR-270



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Wafer Processing Traditional Bonding





Wafer Processing WPA-PRCL-350 and WPA-UVR-270: Bonding

AIT Temporary Bonding Adhesive Film Bonding Process







Wafer Processing Traditional De-Bonding







Wafer Processing WPA-PRCL-350 and WPA-UVR-270: De-Bonding **AIT Temporary Bonding Adhesive Film De-Bonding Process Residual Free Carrier UV Exposure Through Glass Carrier No Cleaning Ply Remove** Thin and/or Carrier **Processed Wafer Residual Free Wafer No Cleaning Clean Peel-Release** Attach Wafer Stack to Tape Frame Peel Release of UV Cured

Film from Wafer

Wafer Processing WPA-PRCL-350 and WPA-UVR-270

Properties

Temporary Bonding Adhesive	WPA-PRCL-350	WPA-UVR-270
Conformable Adhesive Thickness (µm, for Bumps Absorption)	20, 100, 200, 400	20, 100, 200, 400
Adhesive Stretchability (Strain Before Breaking)	>500%	>500%
Adhesive Tg (°C)	-55	-55
Release Liners (Top/Bottom)	50µm/50µm	50µm/50µm
Supported Carrier	Wafer or Glass	Glass
Molt Ponding Tomporature / Prossure	140-160°C	140-160°C
Meit-Bonuing Temperature/Pressure	10-15 psi	10-15 psi
Shear Bond Strength at 25°C to 125°C	350psi-30 psi	350psi-30 psi

Debonding and Cleaning

Temporary Bonding Adhesive	WPA-PRCL-350	WPA-UVR-270	Water-Jet
De-bonding Process: from Carrier	Ply at edge of carrier and peel release	Expose UV followed with ply peel release	Bond Stal
De-bonding Process: from Device Wafer	Peel release	Peel release	
Cleaning Solvent-Process for 🥒 🖉	No cleaning required	No cleaning required	
Cleaning Solvent-Process for Carrier	No cleaning required	No cleaning required	
	AI Technology, Inc	– Wafer Processir	ig Webina

Adhesive Stability				
Temporary Bonding Adhesive	WPA-PRCL-350	WPA-UVR-270		
Stability at 250°C Oxygen-free Condition)	No limitation	>60 min.		
Stability at 275°C Oxygen-free Condition)	>600 min.	Not Recommended		
Stability at 350°C Oxygen-free Condition)	>10 min.	Not Recommended		
/acuum Outgassing Stability	Non-outgassing	Non-outgassing		
olvent and Chemical Stability	Not affected by acid/base and polar solvents	Not affected by acid/base and polar solvents		
Water-Jet and Plating Bath	Not affected by plating	Not affected by plating		
Bond Stability	solution and water	solution and water		



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GD-BGF 7160 & GD-BGF 7090

GD-WPA-PRCL-300



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Wafer Processing

Higher Throughput with *Disposable Carrier*



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Wafer Processing

Higher Throughput with Disposable Carrier

AIT Temporary Bonding Adhesive Films Peel-Release Clean GD-PRCL-350

Bonding, De-Bonding, and Process Steps

- Spin coat or dispense on carrier
- Dry solvent
- Laminate to active side of wafer
- Backgrind with "water" cleaning
- Stress relief
- Via creation
- Lithography, plating, deposition, etc
- De-bond Peel release clean
 - **Dispose carrier with adhesive**

 - Clean carrier



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NO spin coating. NO drying. NO expensive, intensive, time consuming debonding NO cleaning

Bond, process, peel, throw it out. On to the next wafer



Wafer Processing GD-PRCL-350 on Disposable Carrier



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Wafer Processing Traditional Bonding





Wafer Processing GD-PRCL-350: Bonding

Bonding AIT Temporary Bonding Adhesive Film on Disposable Carrier





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Wafer Processing Traditional De-Bonding







Wafer Processing GD-PRCL-350 on Disposable Carrier: De-Bonding



De-Bonding AIT Temporary Bonding Adhesive Film on Disposable Carrier



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(De-taping)

on Tape Frame

Wafer Processing GD-PRCL-350 on Disposable Carrier

Due		
Pro	pel	τιε

Temporary Bonding Adhesive	GD-PRCL-350	
Conformable Adhesive Thickness	20 100 200 40	
(μm, for Bumps Absorption)	20, 100, 200, 40	
Adhesive Stretchability	> E 0.00/	
(Strain Before Breaking)	>500%	
Adhesive Tg (°C)	-55	
Molt Ponding Tomporature (Prossure	140-160°C	
Meit-Bonding remperature/Pressure	10-15 psi	
Shear Bond Strength at 25°C to 125°C	350 psi-30 psi	

Adhesive Stability		
Temporary Bonding Adhesive	GD-PRCL-350	
Stability at 250°C	No limitation	
(Oxygen-free Condition)	Nominitation	
Stability at 275°C	>600 min	
(Oxygen-free Condition)	>000 mm.	
Stability at 350°C	>10 min	
(Oxygen-free Condition)	×10 mm.	
acuum Outgassing Stability Non-outgassin		
	Not affected by	
Solvent and Chemical Stability	acid/base and polar	
	solvents	
Water-Jet and Plating Bath	Not affected by plating	
Bond Stability	solution and water	

Debonding and Cleaning

Temporary Bonding Adhesive	🕜 GD-PRCL-350 🔥
De-bonding Process:	Ambient peel release
from Device Wafer	(0% residual)
Cleaning Solvent-Process for Wafer	No cleaning required
Cleaning Solvent-Process for Carrier	No cleaning required



Carrier Properties			
Temporary Bonding Adhesive	GD-PRCL-350-WS	GD-PRCL-350-SS	GD-PRCL-350-FG
Disposable Flexible Carrier Thickness	50µm	50µm	50µm
Carrier CTE (ppm/ºC)	7	18	17

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Novel Solutions from Al Technology, Inc

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WPA-PRCL-200

GD-BGF 7160 & GD-BGF 7090

GD-WPA-PRCL-300



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Wafer Processing Technology Background



ırce: Omdia ארב איז איז פאר פאר Semiconductors Report - 2020 Silicon Carbide & Gallium Nitride Power Semiconductors



Presentation Roadmap

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GD-WPA-PRCL-300



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Backgrinding Temporary Bonding

Higher Requirements: Where Traditional Backgrinding Adhesives Fall Short

Silicon and Traditional Requirements

- Si wafers relatively soft
- Standard backgrinding tape adequate
 - ~ 200 gm/inch
- No high temperatures
 - Polyolefin or PVC carriers: <70°C</p>
- Some may accommodate bumps

Beyond Slicon: Hard and Brittle Materials

- SiC, Sapphire
- III-V Semiconductors

Beyond Silicon: Backgrinding

- Higher shear force
- Greater heat generation
- Potentially brittle, fragile materials





Backgrinding

Temporary Bonding: Difficult to Grind Materials

Considerations and Requirements

High and stable shear bond strength

- Hard materials: SiC, Sapphire, etc.
- Fragile materials: GaAs, GaN, etc.

Wet and dry etching

Stress relief

Throughput and Yield

- Ease of de-bonding
- Post grind residuals cleaning





Backgrinding Temporary Bonding: Wax

Traditional Backgrinding Tape

- Insufficient for difficult to grind materials
- Lack strength
- Low temperature tolerance

A Different Solution

- Film forming **Wax**
- High bond strength
 - Die shear strength >1500 psi
- Maintain strength up to 100 °C

Disco on GaAs and Wax:

"GaAs is an easily damaged material, so typically wax securing is chosen for grinding due to its strong retaining force." -Disco

Advantages

Low risk of wafer breakage during grinding

Disadvantages

- TTV issues: difficulty in application
- Cleaning step after grinding
 - Risk of wafer breakage

AIT wax solutions eliminate these issues



Backgrinding Temporary Bonding: Wax by AIT

Conformable for high topography

Encapsulate 3μm to 400μm bumps and features

AIT wax films = Low TTV

Eliminates operator inconsistency

High bond strength

Temperature resistance for hard to grind material

Cleaning: IPA Wash





Presentation Roadmap

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WPA-PRCL-350 & WPA-UVR-270

GD-PRCL-350 Product Line

Wafer Backgrinding and Thinning

Special Solutions for Special Material

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GD-BGF 7160 & GD-BGF 7090

GD-WPA-PRCL-300



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Wafer Backgrinding BGF 7090 & BGF 7160: High Bond Strength Wax Films



Wafer Backgrinding WPA-PRCL-200: High Strength Temporary Bonding Adhesive Film



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Wafer Backgrinding

Novel Technology from AIT: Backgrinding Film on Disposable Carriers



Wafer Backgrinding

Backgrinding Film on Disposable Carriers: Equipment

Disposable Carrier Appropriate Equipment Example:

DISCO 'Frame Grinding'



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Wafer Backgrinding GD-BGF 7090 & GD-BGF 7160: Wax Films on Disposable Carriers





Wafer Backgrinding GD-WPA-PRCL-200: Adhesive Film on Disposable Carrier





AIT Backgrinding-Thinning Temporary Bonding Adhesives					
Temporary Bonding Adhesive	BGF 7090	BGF 7120	BGF 7160	WPA-PRCL-200	
Liquid Spin-Coating Version	BGL7080	BGL7120	BGL7160	WPA-PRCL-200L	
Melt-Bonding Temperature	80-100°C	110-130°C	140-160°C	140-160°C	
Shear Bond Strength at 25°C	>1000 psi	>1000 psi	>1000 psi	>300 psi	
Shear Bond Strength at 50°C	>1000 psi	>1000 psi	>1000 psi	>300 psi	
Shear Bond Strength at 75°C	<30 psi	<30 psi	>200 psi	>150 psi	
Shear Bond Strength at 100°C	0 psi	<20 psi	<30 psi	>75 psi	
Suggested Zero Shear	80-100°C	110 120 ⁰ C	140 160°C	Ambient peel-release only	
Removal Temperature		110-150 C	140-160 C	(0% residual)	
Cleaning Solvent-Process for	IPA (Isopropyl	IPA (Isopropyl	IPA (Isopropyl	No cloaning required	
Wafer	Alcohol)	Alcohol)	Alcohol)	No cleaning required	
Cleaning Solvent-Process for	IPA (Isopropyl	IPA (Isopropyl	IPA (Isopropyl	No cleaning required	
Carrier	Alcohol)	Alcohol)	Alcohol)		



Thank you!

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Any Questions?

Visit us on the web: **www.aitechnology.com** Send us an email**: ait@aitechnology.com** Give us a call: **1-(609)-799-9388**

To learn more please go to:

aitechnology.com/products/wafer-processing-adhesives-and-solutions/

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